

Application No.: Not Yet Assigned

Docket No.: 2593-0150PUS1

AMENDMENTS TO THE CLAIMS

1. (Original) An electronic device testing apparatus, for conducting a test by pressing input/output terminals of electronic devices to be tested against contact portions of a test head by a moving means while said electronic devices to be tested are loaded on an electronic device conveying medium, comprising:

one or a plurality of said moving means capable of gripping and conveying to and from said contact portions a plurality of said electronic device conveying media loaded with said electronic devices to be tested at a time.

2. (Original) The electronic device testing apparatus as set forth in claim 1, wherein said moving means is capable of freely selecting the gripping number within the number able to be gripped.

3. (Currently Amended) The electronic device testing apparatus as set forth in claim 1 or 2, wherein said one moving means is capable of freely selecting the gripping number being independent from other moving means.

4. (Currently Amended) The electronic device testing apparatus as set forth in ~~any one of claims 1 to 3~~ claim 1, wherein said any two or more moving means among said plurality of moving means have a substantially overlapping operation range on a contact group as a set of said contact portions.

5. (Original) The electronic device testing apparatus as set forth in any one of claims 1 to 4, wherein said electronic device conveying medium is a strip format or a wafer.

6. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims ~~1 to 5~~ 1 to 4, wherein each of said moving means grips said electronic device conveying medium loaded with said electronic devices to be tested and moves from a loading position of pre-test electronic devices to said contact portions.

7. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims ~~1 to 6~~ 1 to 4, wherein each of said moving means grips said electronic device conveying medium loaded with said electronic devices to be tested and moves from said contact portions to a loading position of post-test electronic devices.

8. (Currently Amended) The electronic device testing apparatus as set forth in any one of claims ~~1 to 7~~ 1 to 4, wherein a sum of the numbers of contact portions in said test head is 2^n ("n" is a natural number).

9. (Original) The electronic device testing apparatus as set forth in claim 8, wherein n=5.

10. (Original) The electronic device testing apparatus as set forth in claim 8, wherein n=6.